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'n	AC	3,201,980	08/1965	Webb							
JD	AD	5,343,748	09/1994	Kease	, et al.						
'n	AE	2,573,286	10/1951	Baker,	et al.						
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æ	"Microscratch and Load Relayation Tests for Ultra-Thin Films" - Wu T. W.										
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EXAMINER		Jonathan Dunla	ip/		DATE CONS	DERED 03	/02/20	07		
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